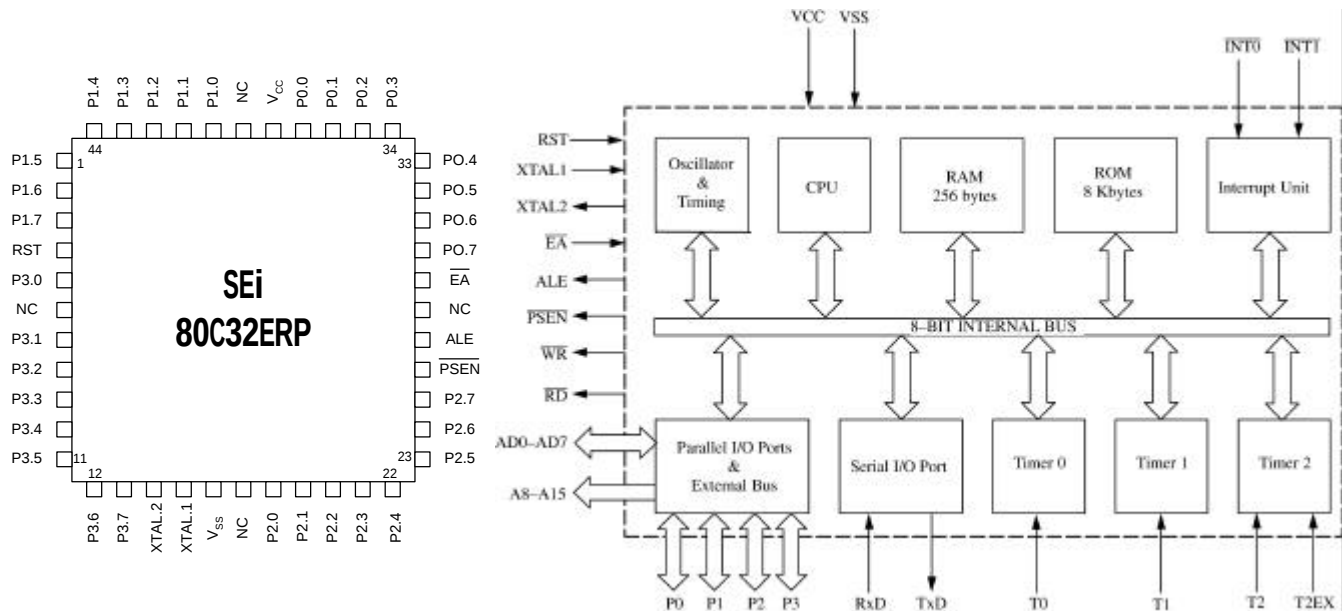




FEATURES:

- CMOS Single-chip 8-bit microcontroller
- RAD-PAK® radiation-hardened against natural space radiation
- Total dose hardness >100 Krad (Si); dependent upon orbit
- Package:
 - 44 pin RAD-PAK® quad flat pack
- Power control modes
- 256 x 8-Bit RAM
- 32 programmable I/O lines
- Three 16-bit timer
- 64K program memory space
- Fully static design
- Boolean processor
- 6 interrupt sources
- Programmable serial port
- 64K data memory space

DESCRIPTION:

Space Electronics' 80C32ERP (RP for RAD-PAK®) high performance CMOS single-chip 8-bit microcontroller features a typical 100krad(Si) total dose tolerance; dependent upon orbit. The 80C32ERP fully static design allows to reduce system power consumption by bringing the clock frequency down to any value without loss of data and greatly enhances the radiation tolerance. Its features include: 256 bytes of RAM, 32 I/O lines, three 16-bit timers, a 6-source, 2-level interrupt structure, a full duplex serial port, and on-chip oscillator and clock circuits. The patented radiation-hardened RAD-PAK® technology incorporates radiation shielding in the microcircuit package. Capable of surviving in space environment, the 80C32ERP is ideal for satellite, spacecraft, and space probe missions. It is available with packaging and screening up to Class S.

TABLE 1. 80C32ERP PIN DESCRIPTION

PIN/PORT	DESCRIPTION
V _{SS}	Circuit ground potential
V _{CC}	Supply voltage during Normal, Idle, and Power Down Operation
RST	High level of RST for 2 machine cycles while oscillator is running resets the device
ALE	Address Latch Enable output for latching during accesses to external memory Can sink/source 8 LS TTL inputs and drive CMOS inputs without an external pullup
PSEN	Program Store Enable output is the read strobe to external Program Memory Activated twice each machine cycle during fetches from external Program Memory Not activated during fetches from internal Program Memory Can sink/source 8 LS TTL inputs and drive CMOS inputs and drive CMOS inputs without an external pullup
EA	When EA is held high, the CPU executes out of internal Program Memory (unless the Program Counter exceeds 1 FFFH) When EA is held low, the CPU executes only out of external Program Memory Must not be floated
XTAL1	Input to inverting amplifier that forms the oscillator Receives the external oscillator signal when an external oscillator is used
XTAL2	Output of the inverting amplifier that forms the oscillator Should be floated when an external oscillator is used
Port 0	8-bit open drain bi-directional I/O port Pins that have 1's written to them float and can be used as high-impedance inputs when in that state Multiplexed low-order address and data bus during accesses to external Program and Data Memory Uses strong internal pullups when emitting 1's Outputs code bytes during program verification Can sink 8 LS TTL inputs
Port 1	8-bit open drain bi-directional I/O port Pins that have 1's written to them are pulled high by internal pullups and can be used as inputs in that state Receives low order address byte during program verification Can sink/source 3 LS TTL inputs and drive CMOS inputs without external pullups 2 inputs are also used for timer/counter 2: - P1.0 [T2]: External clock input for timer/counter 2 - P1.1 [T2EX]: Trigger input for timer/counter 2 to be captured or reloaded causing the timer/counter 2 interrupt
Port 2	8-bit open drain bi-directional I/O port Pins that have 1's written to them are pulled high by internal pullups and can be used as inputs in that state Can sink/source 3 LS TTL inputs and drive CMOS inputs without external pullups
Port 3	8-bit open drain bi-directional I/O port Pins that have 1's written to them are pulled high by internal pullups and can be used as inputs in that state

TABLE 2. 80C32ERP ABSOLUTE MAXIMUM RATINGS

(V_{CC} = 5 V ± 10%, V_{SS} = 0 V, F = 0 to 36 MHz, T_A = -55 to 125 °C UNLESS OTHERWISE SPECIFIED)

PARAMETER	SYMBOL	MIN	MAX	UNIT
Voltage on any pin relative to V _{SS}	V _{SS}	-0.5	V _{CC} + 0.7	V
Voltage on V _{CC} supply relative to V _{SS}	V _{CC}	-0.5	7	V
Operating Temperature	T _A	-55	125	°C
Storage Temperature	T _{STG}	-65	150	°C
Power Dissipation	P _D	--	1	W

TABLE 3. 80C32ERP DC ELECTRICAL CHARACTERISTICS

(V_{CC} = 5 V ± 10%, V_{SS} = 0 V, F = 0 to 36 MHz, T_A = -55 to 125 °C)

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	MAX	UNIT
Input Low Voltage	V _{IL}		-0.5	0.2 V _{CC} - 0.1	V
Input High Voltage (except XTAL, RST)	V _{IH}		0.2 V _{CC} + 1.4	V _{CC} + 0.5	V
Input High Voltage (for XTAL, RST)	V _{IH1}		0.7 V _{CC}	V _{CC} + 0.5	V
Output Low Voltage (Port 1,2,3)	V _{OL}	I _{OL} = 1.6 mA ¹	--	0.45	V
Output Low Voltage (Port 0, ALE, PSEN)	V _{OL1}	I _{OL} = 3.2 mA ¹	--	0.45	V
Output High Voltage (Port 1,2,3)	V _{OH}	I _{OH} = -60 uA V _{CC} = 5 V ± 10% I _{OH} = -25 uA I _{OH} = -10 uA	2.4 -- 0.75 V _{CC} 0.9 V _{CC}	-- -- -- --	V
Output High Voltage (Port 0 in External Bus Mode, ALE PSEN)	V _{OH1}	I _{OH} = -400 uA V _{CC} = 5 V ± 10% I _{OH} = -150 uA I _{OH} = -40 uA	2.4 -- 0.75 V _{CC} 0.9 V _{CC}	-- -- -- --	V
Logical 0 Input Currents Ports 1,2,3	I _{IL}	V _{IN} = 0.45 V	--	-75	uA
Logical 1 to 0 Transition Current (Ports 1,2,3)	I _{TL}	V _{IN} = 2 V	--	-750	uA
Input Leakage Current	ILI	0.45 < V _{IN} < V _{CC}	--	±10	uA
RST Pulldown Resistor	RRST		50	200	kW
Capacitance of I/O Buffer	C _{I/O}	f _c = 1 MHz, T _A = 25 °C	--	10	pF
Power Down Current	I _{PD}	V _{CC} = 2 V to 5.5 V ²	--	75	uA
Power Supply Current	I _{CC}	V _{CC} = 5.5 V ^{1,2}			mA
Freq = 1 MHz I _{CC} op			--	1.8	
I _{CC} idle			--	1	
Freq = 6 MHz I _{CC} op			--	10	
I _{CC} idle			--	--	
Freq ≥ 12 MHz I _{CC} op = 1.25 Freq (MHz) + 5 mA			--	4	
I _{CC} idle = 0.36 Freq (MHz) + 2.7 mA			--	--	

1. I_{CC} is measured with all output pins disconnected; STAL1 is driven with TCLCH, TCHL 5 ns, V_{IL} = V_{SS} + 0.5 V; XTAL2 N.C.; EA = RST = Port 0 = V_{CC}. I_{CC} would be slightly higher if a crystal oscillator used.

2. Capacitance loading on Ports 0 and 2 may cause spurious noise pulses to be superimposed on the VOLS of ALE and Port 3. The noise is due to external bus capacitance discharging onto the Port 0 and Port 2 pins when these pins make the transitions during bus operations. In the worst case (capacitive loading 100 pF), the noise pulse on the ALE line may exceed 0.45V with maximum VOL peak 0.6 V. A Schmitt Trigger use in not necessary.

TABLE 4. EXTERNAL PROGRAM MEMORY CHARACTERISTICS(T_A = -55 to 125 °C, V_{SS} = 0, V_{CC} = 5 V ± 10%, F = 0 to 36 MHz)

PARAMETER	SYMBOL	MIN	MAX	UNIT
ALE Pulse Width	TLHLL			ns
16 MHz		110	--	
20 MHz		90	--	
25 MHz		70	--	
30 MHz		60	--	
36 MHz		50	--	
Address Valid to ALE	TAVLL			ns
16 MHz		40	--	
20 MHz		30	--	
25 MHz		20	--	
30 MHz		15	--	
36 MHz		10	--	
Address Hold After ALE	TLLAX			ns
16 MHz		35	--	
20 MHz		35	--	
25 MHz		35	--	
30 MHz		35	--	
36 MHz		35	--	
ALE to Valid Instrument In	TLLIV			ns
16 MHz		--	185	
20 MHz		--	170	
25 MHz		--	130	
30 MHz		--	100	
36 MHz		--	80	
ALE to PSEN	TLLPL			ns
16 MHz		45	--	
20 MHz		40	--	
25 MHz		30	--	
30 MHz		25	--	
36 MHz		20	--	
PSEN Pulse Width	TPLPH			ns
16 MHz		165	--	
20 MHz		130	--	
25 MHz		100	--	
30 MHz		80	--	
36 MHz		75	--	

TABLE 4. EXTERNAL PROGRAM MEMORY CHARACTERISTICS

(T_A = -55 to 125 °C, V_{SS} = 0, V_{CC} = 5 V ± 10%, F = 0 to 36 MHz)

PARAMETER	SYMBOL	MIN	MAX	UNIT
PSEN to Valid Instrument in 16 MHz	TPLIV	--	125	ns
16 MHz		--	110	
20 MHz		--	85	
25 MHz		--	65	
30 MHz		--	50	
36 MHz		--		
Input Instrument Hold After PSEN	TPXIX	0	--	ns
16 MHz		0	--	
20 MHz		0	--	
25 MHz		0	--	
30 MHz		0	--	
36 MHz		0	--	
Input Instrument Float After PSEN	TPXIZ	--	50	ns
16 MHz		--	45	
20 MHz		--	35	
25 MHz		--	30	
30 MHz		--	25	
36 MHz		--		
PSEN to Address Valid	TPXAV	55	--	ns
16 MHz		50	--	
20 MHz		40	--	
25 MHz		35	--	
30 MHz		30	--	
36 MHz			--	
Address to Valid Instrument in 16 MHz	TAVIV	--	230	ns
16 MHz		--	210	
20 MHz		--	170	
25 MHz		--	130	
30 MHz		--	90	
36 MHz		--		
PSEN Low to Address Float ¹	TPLAZ	--	10	ns
16 MHz		--	10	
20 MHz		--	8	
25 MHz		--	6	
30 MHz		--	5	
36 MHz		--		

1. Not tested.

TABLE 5. EXTERNAL DATA MEMORY CHARACTERISTICS

PARAMETER	SYMBOL	MIN	MAX	UNIT
RD Pulse Width 16 MHz 20 MHz 25 MHz 30 MHz 36 MHz	TRLRH	340 270 210 180 120	-- -- -- -- --	ns
WR Pulse Width 16 MHz 20 MHz 25 MHz 30 MHz 36 MHz	TWLWH	340 270 210 180 120	-- -- -- -- --	ns
Address Hold After ALE 16 MHz 20 MHz 25 MHz 30 MHz 36 MHz	TLLAX	85 85 70 55 35	-- -- -- -- --	ns
RD to Valid Data In 16 MHz 20 MHz 25 MHz 30 MHz 36 MHz	TRLDV	-- -- -- -- --	240 210 175 135 110	ns
Data Hold After RD 16 MHz 20 MHz 25 MHz 30 MHz 36 MHz	TRHDX	0 0 0 0 0	-- -- -- -- --	ns
Data Float After RD 16 MHz 20 MHz 25 MHz 30 MHz 36 MHz	TRHDZ	-- -- -- -- --	90 90 80 70 50	ns
ALE to Valid Data In 16 MHz 20 MHz 25 MHz 30 MHz 36 MHz	TLLDV	-- -- -- -- --	435 370 290 235 170	ns

TABLE 5. EXTERNAL DATA MEMORY CHARACTERISTICS

PARAMETER	SYMBOL	MIN	MAX	UNIT
Address to Valid Data In 16 MHz 20 MHz 25 MHz 30 MHz 36 MHz	TAVDV	-- -- -- -- --	480 400 320 260 190	ns
ALE to WR or RD 16 MHz 20 MHz 25 MHz 30 MHz 36 MHz	TLLWL	150 135 120 90 70	250 170 130 115 100	ns
Address to WR or RD 16 MHz 20 MHz 25 MHz 30 MHz 36 MHz	TAVWL	180 180 140 115 75	-- -- -- -- --	ns
Data Valid to WR Transition 16 MHz 20 MHz 25 MHz 30 MHz 36 MHz	TQVWX	35 35 30 20 15	-- -- -- -- --	ns
Data Setup to WR Transition 16 MHz 20 MHz 25 MHz 30 MHz 36 MHz	TQVWH	380 325 250 215 170	-- -- -- -- --	ns
Data Hold After WR 16 MHz 20 MHz 25 MHz 30 MHz 36 MHz	TWHQX	40 35 30 20 15	-- -- -- -- --	ns
RD Low to Address Float 16 MHz 20 MHz 25 MHz 30 MHz 36 MHz	TRLAZ	-- -- -- -- --	0 0 0 0 0	ns

TABLE 5. EXTERNAL DATA MEMORY CHARACTERISTICS

PARAMETER	SYMBOL	MIN	MAX	UNIT
RD or WR High to ALE High	TWHLH			ns
16 MHz		35	90	
20 MHz		35	60	
25 MHz		25	45	
30 MHz		20	40	
36 MHz		20	40	

TABLE 6. SERIAL PORT TIMING - SHIFT REGISTER MODE (VALUES IN NS) ¹

PARAMETER	SYMBOL	MIN	MAX	UNIT
Serial Port Clock Cycle Time	TXLXL			ns
16 MHz		750	--	
20 MHz		600	--	
25 MHz		480	--	
30 MHz		400	--	
36 MHz		330	--	
Output Data Setup to Clock Rising Edge	TQVXH			ns
16 MHz		563	--	
20 MHz		480	--	
25 MHz		380	--	
30 MHz		300	--	
36 MHz		220	--	
Output Data Hold After Clock Rising Edge	TXHQX			ns
16 MHz		63	--	
20 MHz		90	--	
25 MHz		65	--	
30 MHz		50	--	
36 MHz		45	--	
Input Data Hold After Clock Rising Edge	TXHDX			ns
16 MHz		0	--	
20 MHz		0	--	
25 MHz		0	--	
30 MHz		0	--	
36 MHz		0	--	
Clock Rising Edge to Input Data Valid	TXHDV			ns
16 MHz		--	563	
20 MHz		--	450	
25 MHz		--	350	
30 MHz		--	300	
36 MHz		--	250	

1. Not tested.

TABLE 7. EXTERNAL CLOCK DRIVE CHARACTERISTICS (XTAL1)

PARAMETER	SYMBOL	MIN	MAX	UNIT
Oscillator Frequency	FCLCL	--	36	MHz
Oscillator Period	TCLCL	27.8	--	ns
High Time	TCHCX	5	--	ns
Low Time	TCLCX	5	--	ns
Rise Time	TCLCH	--	5	ns
Fall Time	TCHCL	--	5	ns

FIGURE 1. EXTERNAL CLOCK DRIVE WAVEFORMS

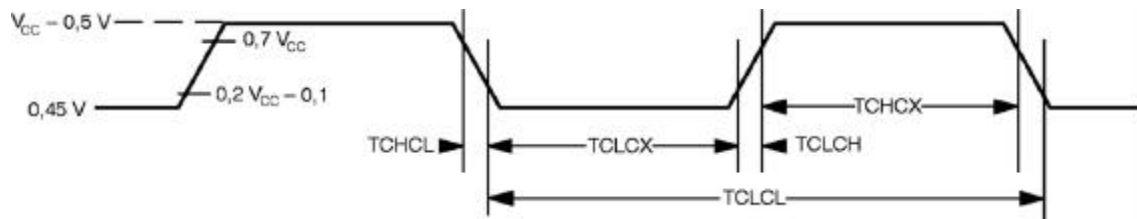


FIGURE 2. EXTERNAL PROGRAM MEMORY READ CYCLE

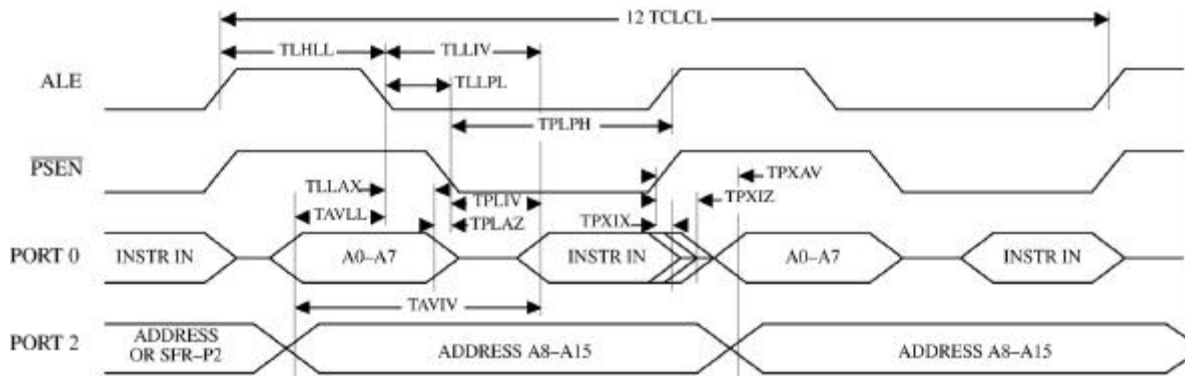


FIGURE 3. EXTERNAL DATA MEMORY WRITE CYCLE

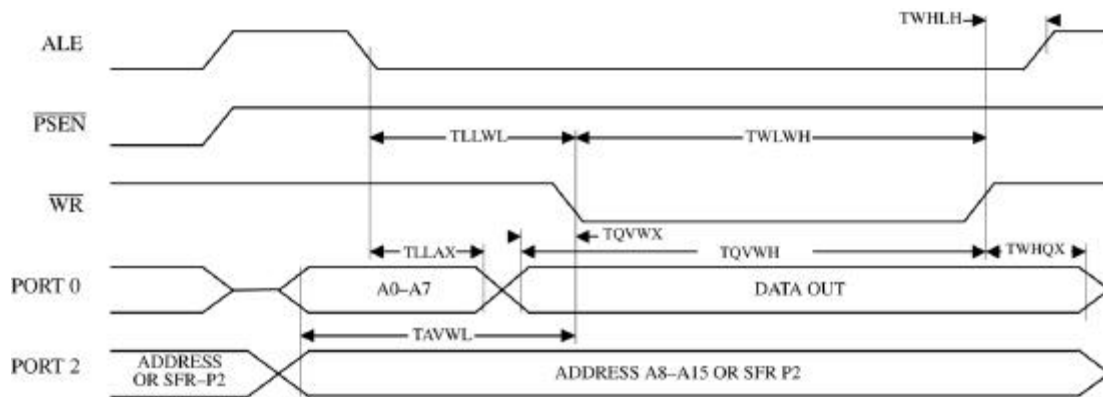


FIGURE 4. EXTERNAL DATA MEMORY READ CYCLE

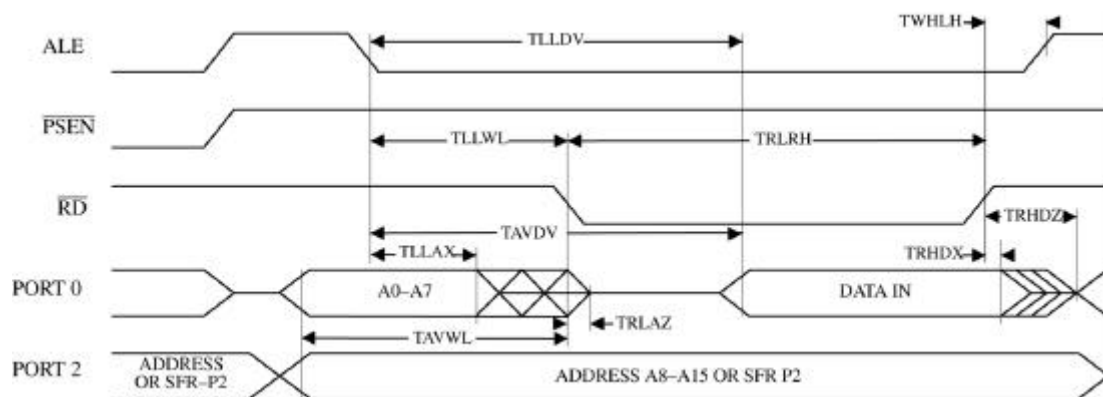
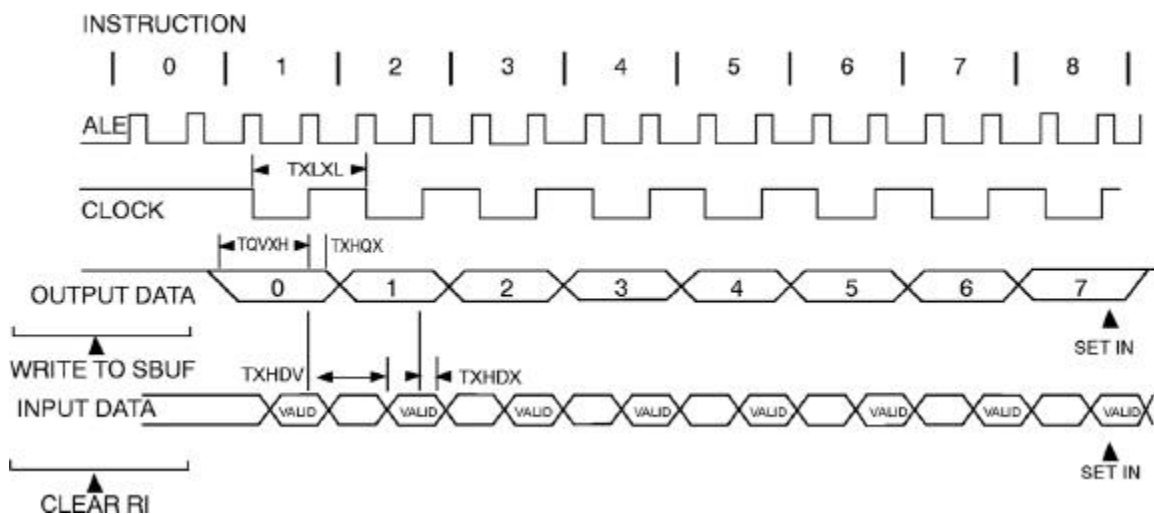
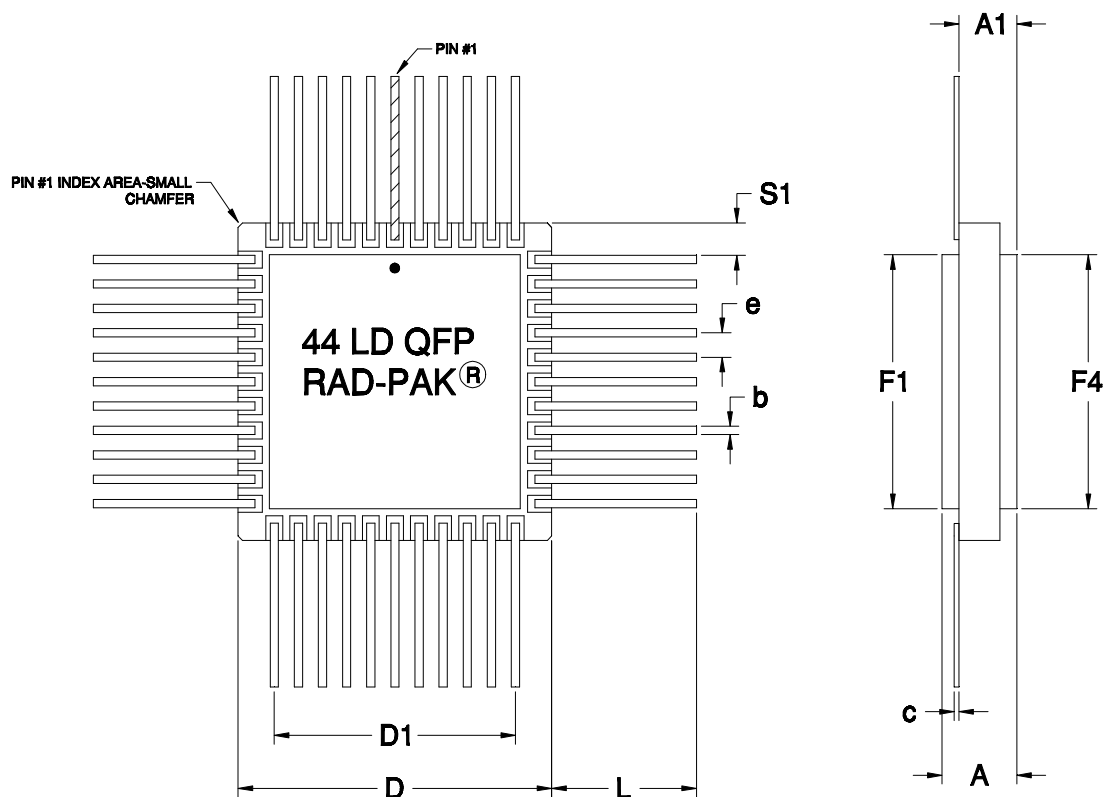


FIGURE 5. SHIFT REGISTER TIMING WAVEFORM





44 PIN RAD-PAK® QUAD FLAT PACKAGE

SYMBOL	DIMENSION		
	MIN	NOM	MAX
A	0.139	0.153	0.167
b	0.015	0.017	0.019
c	0.007	0.010	0.010
D	0.642	0.650	0.658
D1	0.500 BSC		
e	0.050 BSC		
S1	0.013	0.067	--
F1	0.495	0.500	0.525
F4	0.469	0.475	0.481
L	0.265	0.275	0.285
A1	0.097	0.108	0.199
N	44		

Q44-03

Note: All dimensions in inches

Important Notice:

These data sheets are created using the chip manufacturers published specifications. Space Electronics verifies functionality by testing key parameters either by 100% testing, sample testing or characterization.

The specifications presented within these data sheets represent the latest and most accurate information available to date. However, these specifications are subject to change without notice and Space Electronics assumes no responsibility for the use of this information.

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